

Precise and Fast Film Thickness Evaluation with Fiber Optic Spectrometer

Basic Information

- Place of Origin:
- Brand Name:
- Certification:
- Model Number:
- Minimum Order Quantity:
- Price:
- Packaging Details:
- Delivery Time:
- 90-120 working days • Payment Terms: T/T, Western Union

CHINA

JINSP

ISO9001

SR100Q

Negotiable

International Shipping Pakcage

100PCS/90-120 days

1

• Supply Ability:



Product Specification

- Spectrual Range:
- Effective Pixels:
- Qutuam Efficiency:
- SNR:
- 200nm 1100nm 1024*122 QE92%peak@650nm, 83%@232nm 1000:1



More Images

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Our Product Introduction

92% High Quantum Spectrometer for Film Thickness Measurement

The evolution of thin film applications demands equally advanced metrology solutions. Photoelectric techniques meet this challenge with their gentle yet rapid measurement capabilities. By incorporating Al-driven analysis, these systems provide actionable insights for process optimization and next-generation material engineering.

The JINSP SR100Q spectrometer is integrated with the Hamamatsu S7031, a scientific-grade TE-cooled area array CCD chip. With a pixel size of up to 24*24µm and excellent quantum efficiency of up to 92%, it ensures high response in the ultraviolet band and effectively improves the sensitivity and SNR of weak signals. Furthermore, it can realize excellent spectrum signals, and stable and reliable performance based on the advanced high-resolution light path and low-noise, high-speed FPGA signal processing chip.

Product Parameters:

| Detector | Chip Type | Back-illuminated TE-cooled Hamamatsu S7031 | |
|--------------------------|-----------------------|--|--|
| | Effective Pixel | 1024*122 | |
| | Pixel Size | 24*24µm | |
| | Sensing Area | 24.576*2.928mm | |
| Optical Parameters | Optical Design | F/4 cross-type | |
| | Numerical Aperture | 0.13 | |
| | Focal Length | 100mm | |
| | Entrance Slit Width | 10µm,25µm,50µm,100µm,200µm (customizable) | |
| | Fiber Interface | SMA905,free space | |
| Electrical Parameters | Integration Time | 8ms-3600s | |
| | Data Output Interface | USB3.0,RS232,RS485,20pin connector | |
| | ADC Bit Depth | 16-bit | |
| | Power Supply | 5V | |
| | Operating Current | <3.5A | |
| Physical Parameters | Operating Temperature | 10 ~40 | |
| | Storage Temperature | -20 ~60 | |
| | Operating Humidity | <90%RH (no condensation) | |
| | Dimensions | 180mm*120mm*50mm | |
| | Weight | 1.2kg | |

List of Product Models:

| Model | Spectral Range(nm) | Resolution(nm) | Slit(µm) |
|------------|---------------------|----------------|----------|
| | | 6.8 | 200 |
| SR100Q-G21 | 200~950 | 2.2 | 50 |
| SR100Q-G22 | 350~1100 | 1.5 | 25 |
| | | 1.0 | 10 |
| SR100Q-G23 | 200~775 | 1.6 | 50 |
| SR100Q-G24 | 350~925 | 1.0 | 25 |
| | | 0.7 | 10 |
| SR100Q-G25 | 532~690(4400cm-1*)* | 13cm-1 | 50 |
| SR100Q-G26 | 638~800(3200cm-1)* | 10cm-1 | 25 |
| SR100Q-G27 | 785~1050(3200cm-1)* | 11cm-1 | 50 |

Note: The*are primarily designed for Raman applications, with the corresponding Raman.

Technical Characteristics:

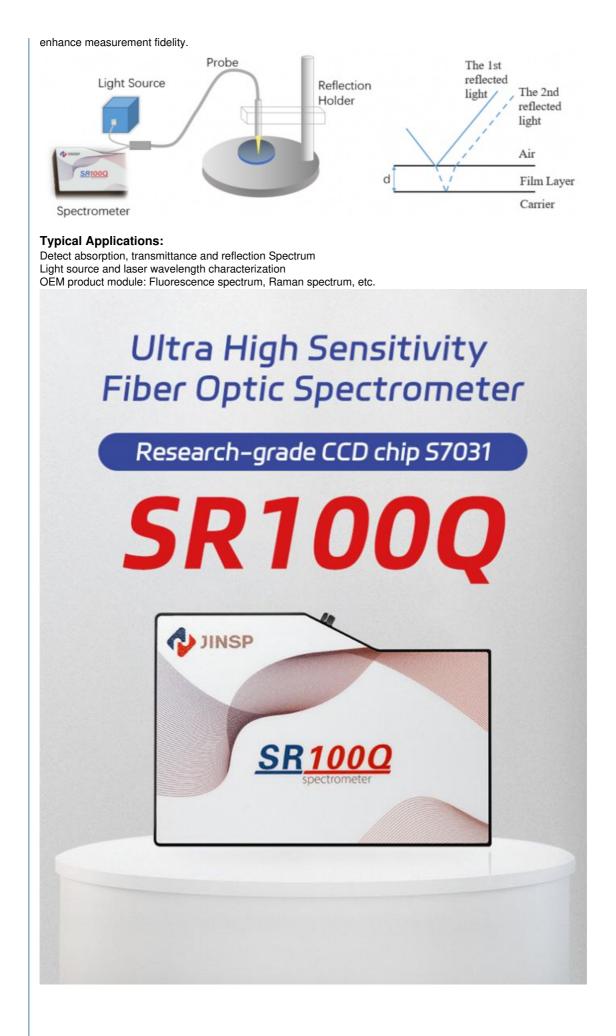
High quantum efficiency, 92%peak@650nm, 83%@232nm

High SNR: Ultra-low dark noise under long integration time, SNR is as high as 1000:1

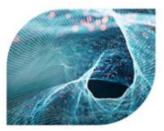
Noise-free clear processing of weak signal in long exposure, strong adaption to environment Low-noise and high-speed circuit: USB3.0

Measurement Method:

Light guided through a fiber probe reflects at the film's air-facing and substrate-facing surfaces. The spectrometer records their interference, from which thickness (d) is extracted using the extremum method (θ , n, and spectral extrema). Denser fringes indicate greater thickness, while longer wavelengths reduce fringe density. Appropriate spectral range and resolution selection



Technical Characteristics



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Low-noise and high-speed circuit: USB3.0

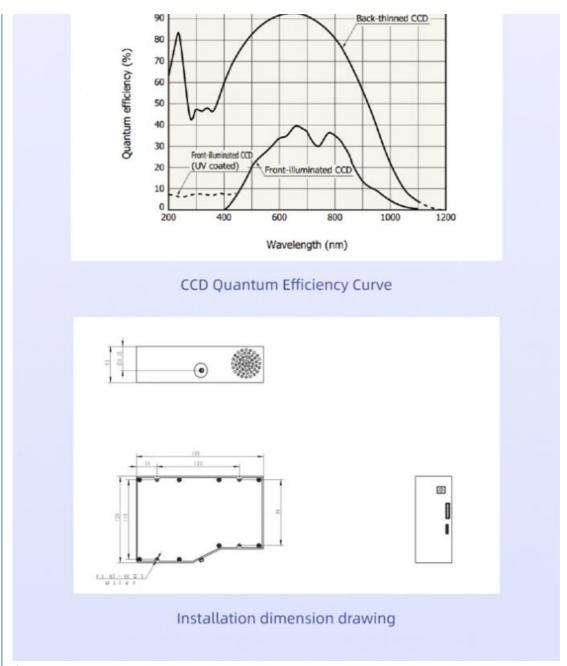
Typical Applications

Detect absorption, transmittance and reflection Spectrum

Light source and laser wavelength characterization

OEM product module: Fluorescence spectrum, Raman spectrum, etc.





Company Introduction:

JINSP Company Limited, abbreviated as "JINSP", is a professional supplier with over 17 years of experience in spectral detection technology products, including Raman, FT-IR, LIBS technologies, etc. After 17 years of technology accumulation, the company's core key technologies have reached the international leading position at the level, and the cumulative number of patent applications exceeded 200.

In addition to its main headquarters located in the bustling city of Beijing, JINSP has established a fully owned subsidiary manufacturing facility situated in the province of Jiangsu, China.

JINSP Company received ISO9001:2015, ISO14001:2015, and ISO45001:2018 certifications. JINSP can provide required certifications, such as certification by the Ministry of Public Security or National Institute of Metrology, Environmental Level Certification, IP Level Certification, CE Certification, Transport Identification Report, EU ECAC certification, German ICT Security Testing, etc.

Company Profile









Exhibition











Certifications



A1:We will send you manual and guide vedio in English,it can teach you how to operate the spectrometer. Also our technicians will offer professional tecnical opearation meetings. Q2: Can your offer a operation traning? A2: Your technicians can come to our factory for a training. Jinsp engineers can go to your place for local support (installation, training, debugging, maintenance). Q3: What's your website? A3: You can visit:www.jinsptech.com Q4: What about your quality assurance? A4: We have a quality inspection team. All goods will go through quality inspection before shipment. We can send you pictures for inspection.

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|-----------------------|------------------------------------|---|---|
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